OTPE		Sheet <u>1</u> of <u>1</u>
Substitute Form P70-1449 (Modified) Substitute Form P70-1449 Oal Department of Commerce Part and Trademark Office	Attorney's Docket No. 07977-213002	Application No. 09/455,991
Information Disclosure Statement by Applicant	Applicant Ohtani, et al.	
(Usa (Cryal Special if necessary) (37 CFR §1.98(b))	Filing Date December 6, 1999	Group Art Unit 2815

	U.S. Patent Documents						
Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
(D)	AA	6 365 933	Apr 2, 2002	Yamazaki et al.	_		
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	AC						
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	AE						
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	Foreign Patent Documents or Published Foreign Patent Applications							
Examiner	Desig.	Document	Publication	Country or			Trans	lation
Initial	ן מו	Number	Date	Patent Office	Class	Subclass	Yes	No
	AL							
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	AN							
	AO							
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· ·	Other Documents (include Author, Title, Date, and Place of Publication)			
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P	AQ	O. Schoenfeld et al., "Crystallization of amorphous silicon by NiSi ₂ precipitates." Thin Solid Films 261 (1995) 236-240.		
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Examiner Signature	Date Considered //23/0v
EXAMINER: Initials citation considered. Draw line through citation if no next communication to applicant.	
	Substitute Disclosure Form (PTO-1449)

(37 CFR §1.98(b))

Form PTO-1449

U.S. Department of Commerce Patent and Trademark Office

Attorney's Docket No. 07977-213002

Application No. 09/455,991

Information Disclosure Statement by Applicant (Use several sheets if necessary) Applicant Ohtani, et al.

Filing Date
December 6, 1999

Group Art Unit 2815

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	AW				1			

Examiner Signature	
	Data Considered
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